XA-10644
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

HAGA, Shunichi et al.

Intl. Appln. No.: PCT/JP2005/003402

Intl. Filing Date: 1 March 2005

For: OBSERVATION DEVICE AND BINOCULARS

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Attn: Mail Stop PCT, DO/EO/US

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

Document AF on the attached List was cited in the specification, on page 1, and its relevance is indicated therein. Documents AA and AG-AM were cited in the International Search Report (copy attached).

Respectfully submitted,

Reg. No. 31,568

MWS:sjk

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September 26, 2006

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FORM PTO-1449					Atty. Docket No.			Appln. No.	
INFORMATION DISCLOSURE STATEMENT LIST OF DOCUMENTS CITED BY APPLICANTS					XA-10644				
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					HAGA, Shuni	chi et	al.		
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			U.S. PATI	ENT DO	CUMENTS				
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	AF	3070429	05/26/00	Japa	n			Abstract	
	AG	2001-343593	12/14/01	Japa	n			Abstract	
	AH	7-49456	02/21/95	Japa	n			Abstract	
	AI	2002-341254	11/27/02	Japa	n			Abstract	
	AJ	2002-341256	11/27/02	Japa	n			Abstract	
	AK	9-304705	11/28/97	Japa	n			Abstract	
	AL	2000-147372	05/26/00	Japa	n			Abstract	
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